Notice of References Cited

Application/Control No. 10/080,017	Reexamination	Applicant(s)/Patent Under Reexamination NAIR ET AL.		
Examiner	Art Unit			
Xiuqin Sun	2863	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,408,429	06-2002	Marrion et al.	717/100
	В	US-2002/0122582 A1	09-2002	Masuda et al.	382/141
	O	US-2002/0116666 A1	08-2002	Perez et al.	714/38
	D	US-6,177,955	01-2001	Downen et al.	348/189
	Е	US-6,212,496	04-2001	Campbell et al.	704/221
	F	US-5,798,814	08-1998	Konuma, Toshimitsu	349/172
	G	US-4,963,824	10-1990	Hsieh et al.	324/763
	Н	US-4,756,017	07-1988	Bush, Gary K.	379/23
	ı	US-6,353,466	03-2002	Park, Kum Sung	349/58
	J	US-			
	Ķ	UŞ-			
	L	US-		·	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			-		
	0		·			
	Р					
	Q					·
	R				·	
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	х	

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.